

**Notice of References Cited**

Application/Control No.

10/536,638

Applicant(s)/Patent Under

Reexamination

VERHAEGH ET AL.

Examiner

Hyun J. Hong

Art Unit

2623

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-2001/0021999	09-2001	Seifert, Nils	725/87
*	B US-2004/0103437	05-2004	Allegrezza et al.	725/095
*	C US-5,612,742	03-1997	Krause et al.	375/240.25
*	D US-6,018,359	01-2000	Kermode et al.	725/101
E	US-			
F	US-			
G	US-			
H	US-			
I	US-			
J	US-			
K	US-			
L	US-			
M	US-			

**FOREIGN PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N					
O					
P					
Q					
R					
S					
T					

**NON-PATENT DOCUMENTS**

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
U	
V	
W	
X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a))  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.